**PATENT ASSIGNMENT COVER SHEET**

**SUBMISSION TYPE:** CORRECTIVE ASSIGNMENT

**NATURE OF CONVEYANCE:** Corrective Assignment to correct the REMOVE APPLICATION 11759915 AND REPLACE IT WITH APPLICATION 11759935 previously recorded on Reel 040925 Frame 0001. Assignor(s) hereby confirms the RELEASE OF SECURITY INTEREST.

**RESUBMIT DOCUMENT ID:** 505812151

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**CORRESPONDENCE DATA**

Fax Number: (800)494-7512

*Correspondence will be sent to the e-mail address first; if that is unsuccessful, it will be sent using a fax number, if provided; if that is unsuccessful, it will be sent via US Mail.*

Phone: 202.370.4750

Email: ipteam@cogencyglobal.com

Correspondent Name: JOANNA MCCALL

Address Line 1: 1025 VERMONT AVE NW, SUITE 1130

Address Line 2: COGENCY GLOBAL INC.

Address Line 4: WASHINGTON, D.C. 20005

**ATTORNEY DOCKET NUMBER:** 1143365 FIX 040925/001

**NAME OF SUBMITTER:** RICK HARRISON

**DATE SIGNED:** 02/17/2020

Total Attachments: 305

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RELEASE OF SECURITY INTEREST IN INTELLECTUAL PROPERTY

THIS RELEASE OF LIEN (this “Release”) is made as of September 12, 2016 (the “Effective Date”) by Morgan Stanley Senior Funding, Inc., as collateral agent (the “Agent”) in favor of Freescale Semiconductor, Inc. (the “Issuer”). Capitalized terms not defined herein shall have the meanings ascribed to such terms in the 6% Notes Security Agreement (as defined below).

WHEREAS, the Issuer entered into that certain amended and restated indenture (the “Amended 6% Indenture”), dated as of December 7, 2015 (as amended, amended and restated, supplemented or other modified from time to time prior to the date hereof) which amended and restated the Indenture dated as of November 1, 2013, pursuant to which the Issuer issued $960,000,000 aggregate principal amount of 6.000% senior secured notes due 2022 (the “6% Notes”) to the holders thereof;

WHEREAS, In connection with its obligations under the 6% Notes (the “Obligations”), the Issuer is party to that certain Security Agreement, dated as of November 1, 2013 (as amended, amended and restated, supplemented or otherwise modified from time to time prior to the date hereof, including pursuant to the Amendment to Security Agreement dated as of December 7, 2015), between the Agent, the Issuer and each of the other Grantors from time to time party thereto (as defined therein) (as so amended, the “6% Notes Security Agreement”);

WHEREAS, In connection with the Amended 6% Indenture and the 6% Notes Security Agreement, the Issuer entered into that certain Assignment and Assumption, dated as of December 7, 2015, which assigned to the Agent, for its benefit, a continuing first priority security interest in and to all of its right, title and interest in, to and under all of its Patents listed on Schedule A hereto (the “Patents”) as security for the due and punctual payment and performance in full, whether at stated maturity, by required prepayment, declaration, acceleration, demand or otherwise, of the Obligations; and

WHEREAS, Agent acknowledges full performance of the Obligations and accordingly requests a specific release of the security interest granted and recorded against all of the Patents of the Issuer pursuant to the 6% Notes Security Agreement (including, but not limited to, those items set forth on Schedule A hereto and/or identified in the Security Agreements).

NOW, THEREFORE, for good and valuable consideration, the receipt and sufficiency of which are hereby acknowledged, the Agent hereby, on behalf of itself and its respective successors and assigns, hereby: (i) fully releases and discharges any and all liens, security interests, right, title and interest it may have, in whole or in part, in, to and under all of the Patents of the Issuer granted to the Agent pursuant to the 6% Notes Security Agreement, together with the goodwill of the business symbolized thereby and all applications and registrations related thereto; (ii) re-assigns to the Issuer any and all such right, title and interest that it may have in any such Patents; (iii) agrees that it shall execute all other documents and do all other acts necessary to relinquish and effect the release of such rights to the Issuer; and (iv) authorizes and requests that the United States Patent and Trademark Office note and record the release hereby given and any other filings necessary to evidence the release and termination of the Agent’s rights under each of the Amended 6% Indenture and the 6% Notes Security Agreement, with respect to any such Patents.

Notwithstanding anything herein (or in any other document, communication or filing relating hereto by any person) to the contrary, the Agent is authorizing solely the release of the security interests granted pursuant to the 6% Notes Security Agreement and the Issuer’s obligations under the 6% Notes, and not any other liens or security interests at any time granted by the Issuer or any other Grantor in favor of Morgan Stanley Senior Funding, Inc. or in favor of any other person.
This Release may be executed in any number of counterparts and by different parties in separate counterparts, each of which when so executed shall be deemed to be an original and all of which taken together shall constitute one and the same agreement.

This Release shall be governed by, and construed and interpreted in accordance with, the laws of the State of New York.

[Remainder of Page Intentionally Left Blank]
IN WITNESS WHEREOF, the Administrative Agent has caused this Release to be executed, on behalf of itself and the Lenders, by its duly authorized representative effective as of the Effective Date.

MORGAN STANLEY SENIOR FUNDING, INC.,
as Administrative Agent

By: ____________________________
   Name: Robbie Pearson
   Title: Authorized Signatory

[Signature Page to IP Release – NXP (Patents)]
# INTELLECTUAL PROPERTY

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## INTELLECTUAL PROPERTY

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<td>Z-axis accelerometer with at least two gap sizes and travel stops disposed outside an active capacitor area</td>
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<td>Method of semiconductor fabrication incorporating disposable spacer into elevated source/drain processing.</td>
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<td>Method for treating a semiconductor surface to form a metal-containing layer.</td>
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### Freescale Semiconductor, Inc. U.S. Patent Applications

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<td>A contention free parallel access system and a method for contention free parallel access to a group of memory banks</td>
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<td>US</td>
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<td>Microprocessor having a low-power mode and a non-low power mode, data processing system and computer program product</td>
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<td>US</td>
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<td>US</td>
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<td>Semiconductor Device Having Localized Extremely Thin Silicon on Insulator Channel Region</td>
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